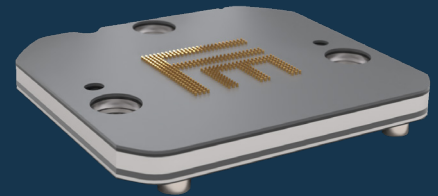


FeinProbe II[®]

New Feinmetall ceramic head design as vertical test solution. The precise ceramic design enables high quality, high design flexibility as well as reliable and fast-automated assembly or maintenance of the integrated contact elements.



Key features:



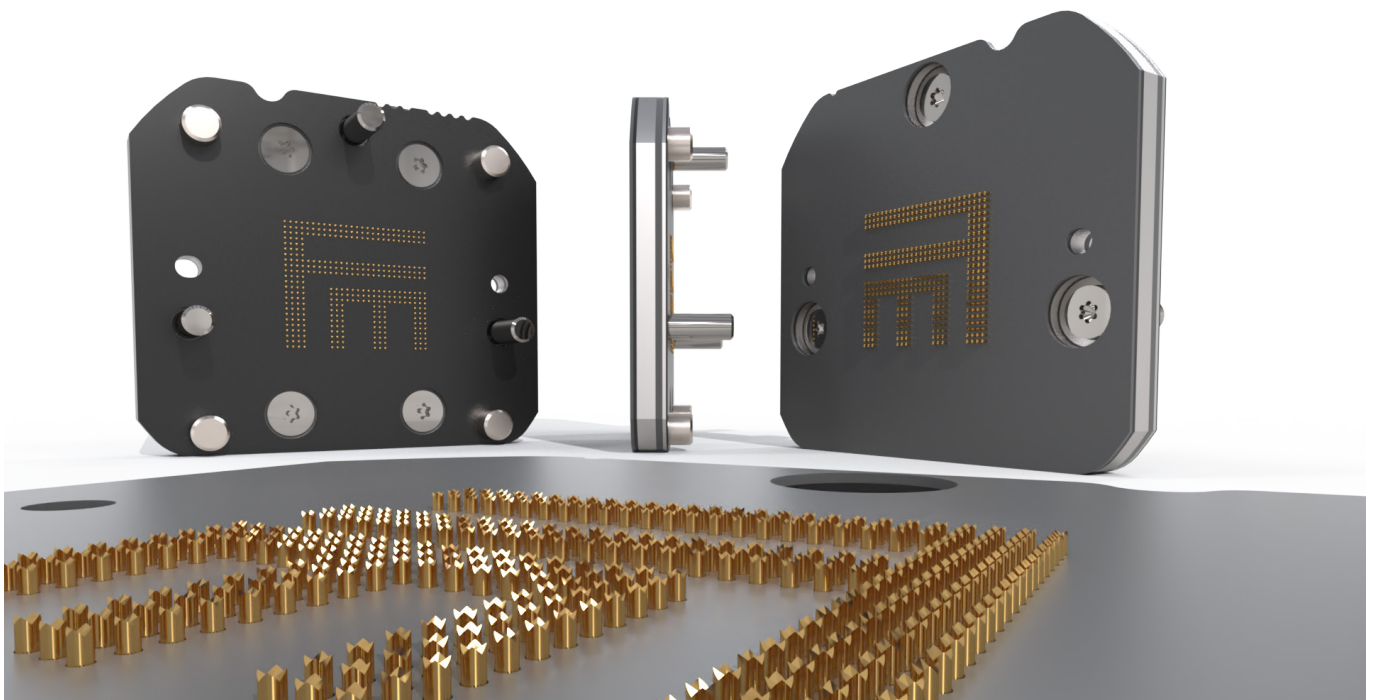
Low cost test solution

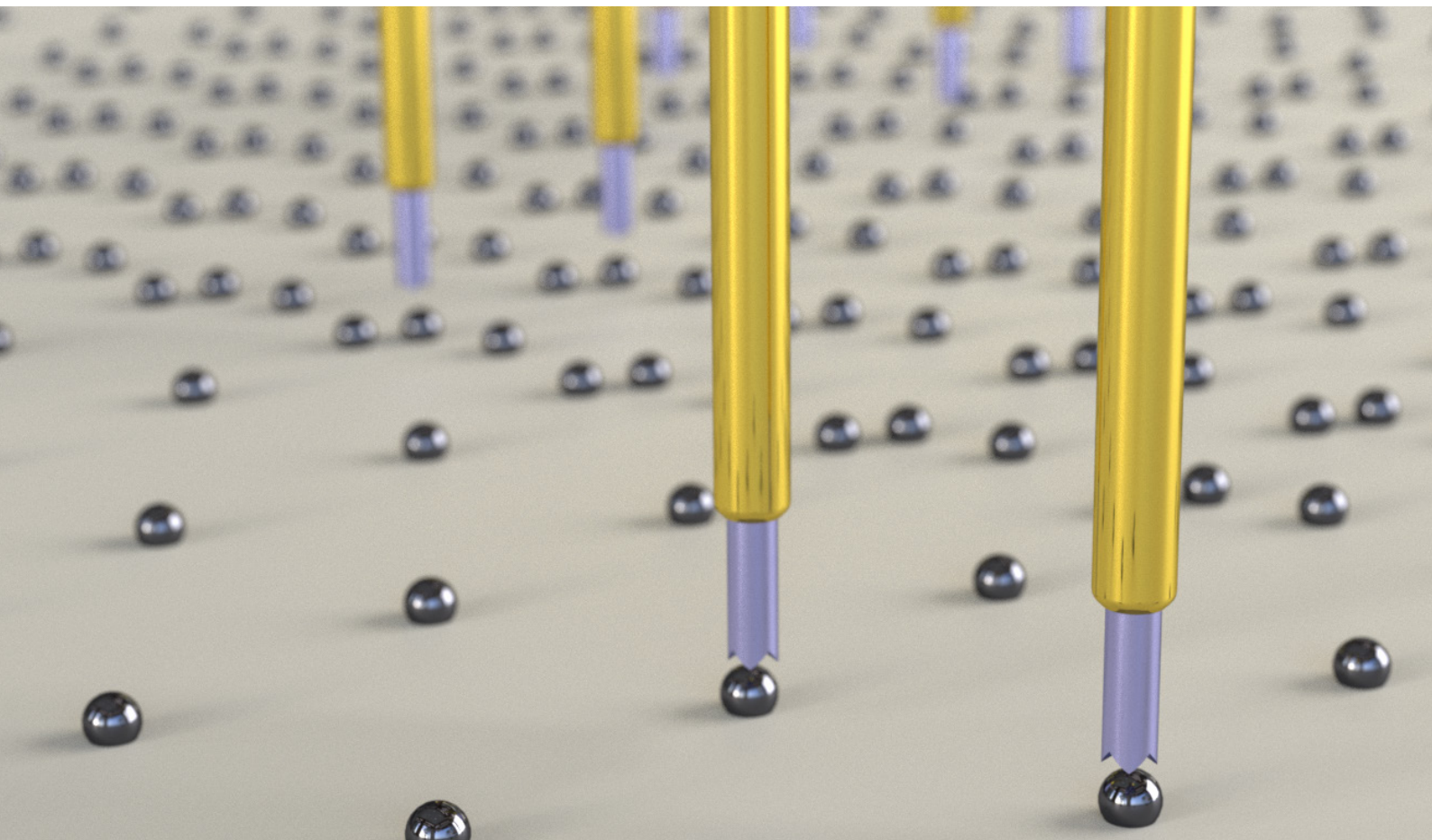


Short lead time



5G proven technology





FeinProbe II[®]	Probe Parameters*	Unit
Spring Probe Length	4.7 - 8.6	mm
Recommended Overdrive (OD)	150 - 200	µm
Maximum OD	200 - 600	µm
Contact Force @ rec. OD	4.5 – 15.1	cN
Contact Force @ max. OD	5.5 – 24.9	cN
Tip Extension (New Probe)	310 - 1110	µm
Minimum Pitch Full Array	150 - 500	µm
Minimum Bump Diameter	100 - 220	µm
Alignment	± 30	µm
Electrical Planarity	< 75	µm
Spring Probe Resistance	< 0.2	Ohm
Self-Inductance	1.7 – 2.37	nH
CCC (DC) @ Ambient Temperature	200 - 2100	mA
Test Temperature	-55 to +150	°C
Available Tip Shapes	Pointed / Wedge / Crown	

***Range depends on selected spring contact probe**